

The Development of HiPIMS Multilayer SIS film coatings on Copper for SRF Applications

9th international thin film workshop, 15-18 March 2021

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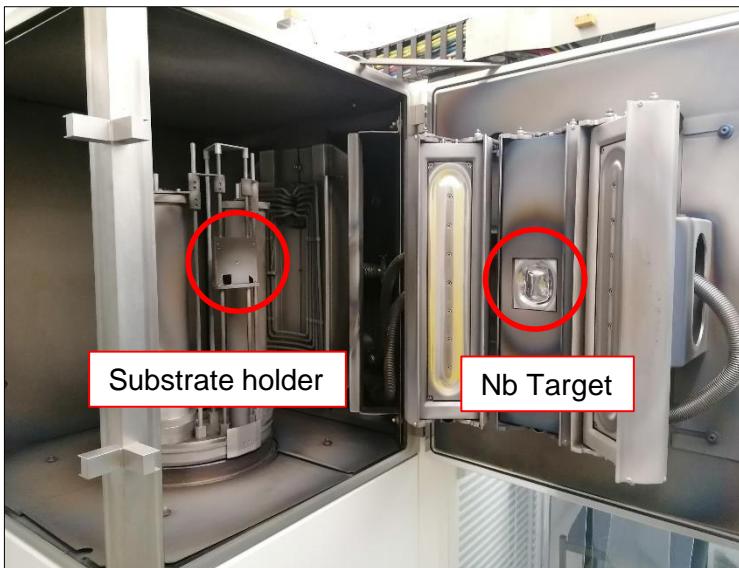
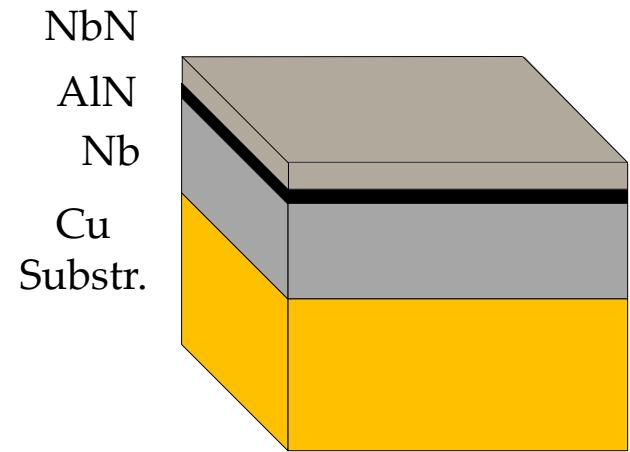
⁵ LNL/INFN, Legnaro, Italy



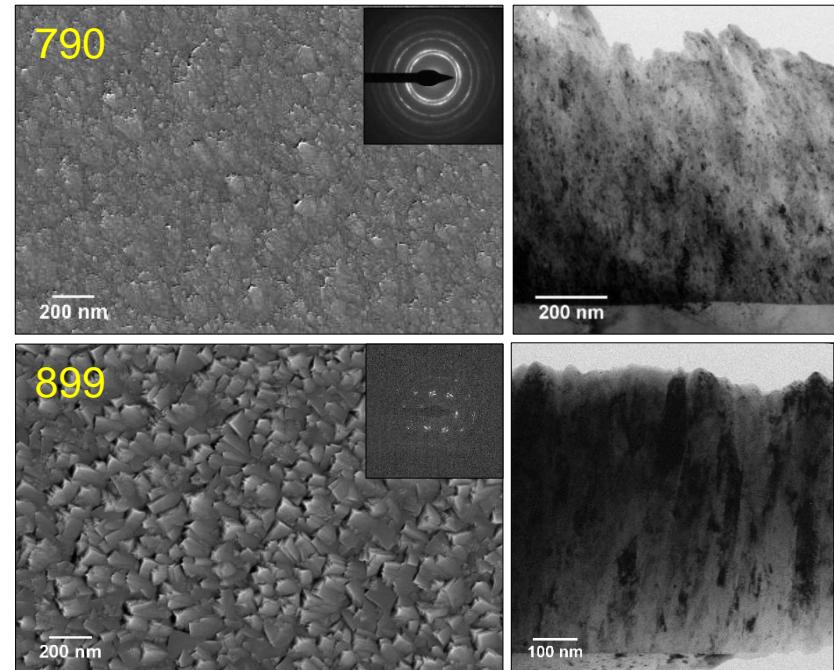
EASITrain – European Advanced Superconductivity Innovation and Training. This Marie Skłodowska-Curie Action (MSCA) Innovative Training Networks (ITN) has received funding from the European Union's H2020 Framework Programme under Grant Agreement no. 764879

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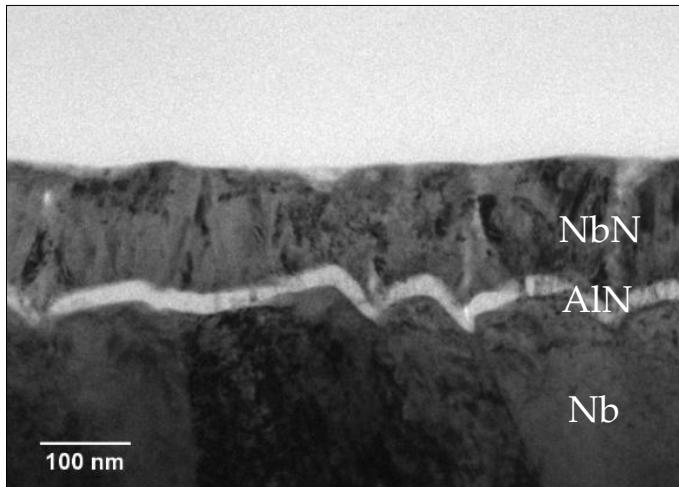
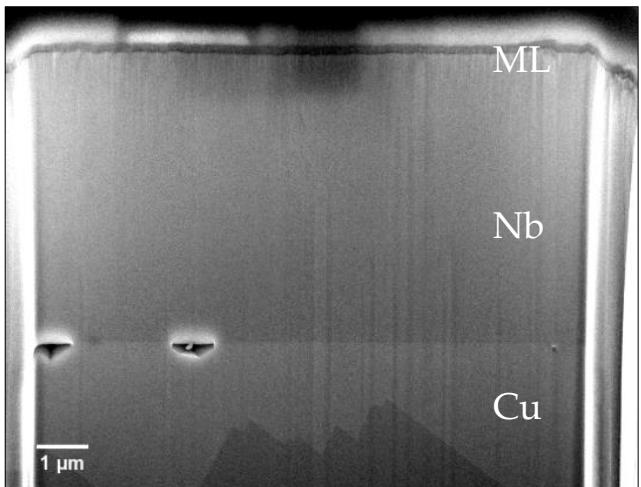
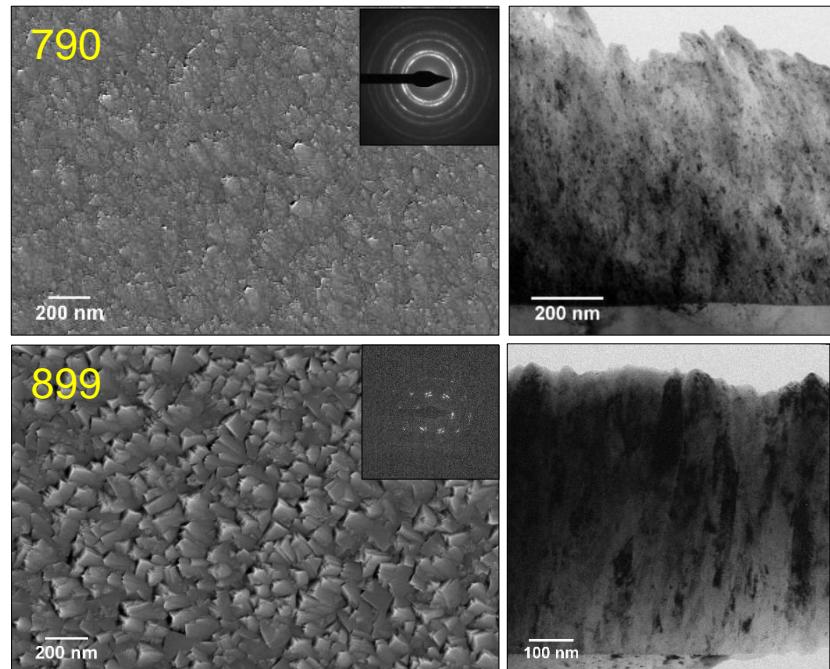
1. DC MS NbN optimisation
 - DC MS based SIS films
2. HiPIMS Nb optimisation
 - HiPIMS Nb + DC MS NbN SIS films
3. HiPIMS NbN optimisation
 - HiPIMS SIS films

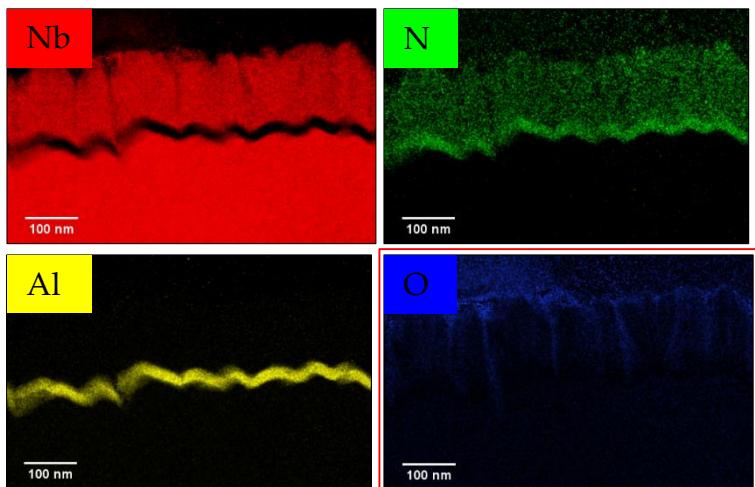


- Optimised DC MS NbN recipe
 - Highest H_{c1} = 13.0 mT (790)
 - Highest T_c = 16.1 K (899)

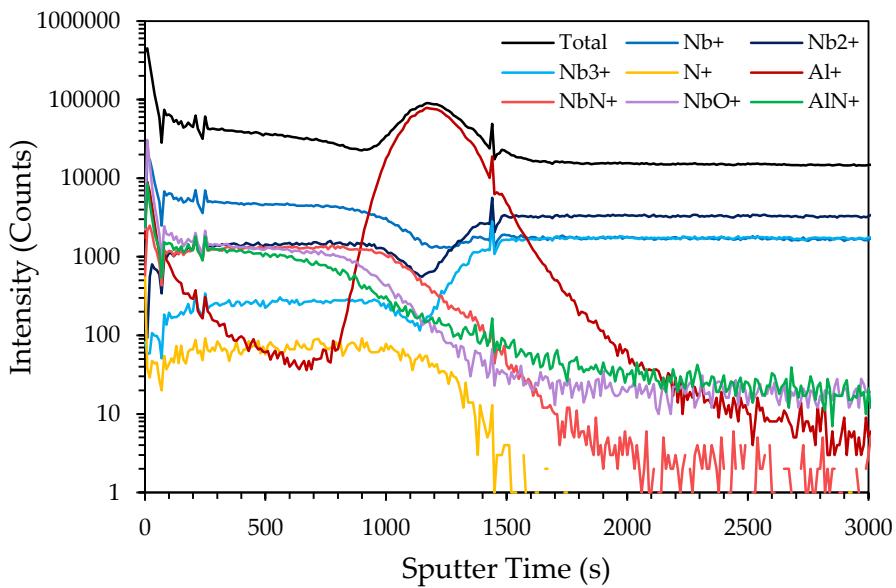


- Optimised DC MS NbN recipe
 - Highest H_{c1} = 13.0 mT (790)
 - Highest T_c = 16.1 K (899)
- DC MS SIS film
 - Table rotated during coating
- Poor interface adhesion
- Rough Nb layer

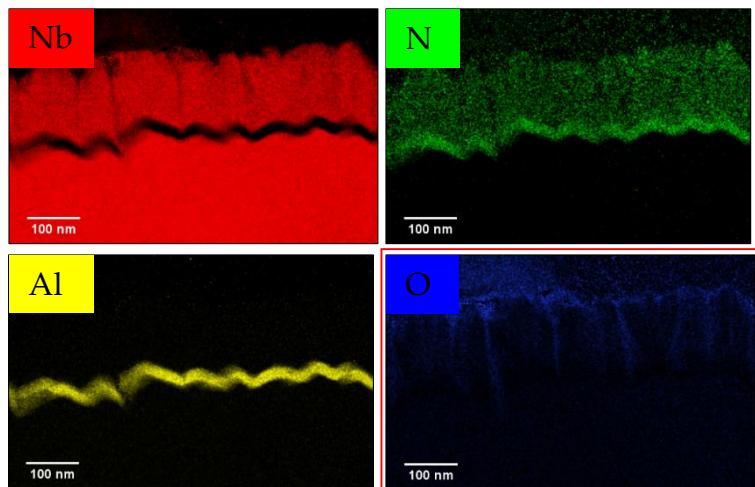




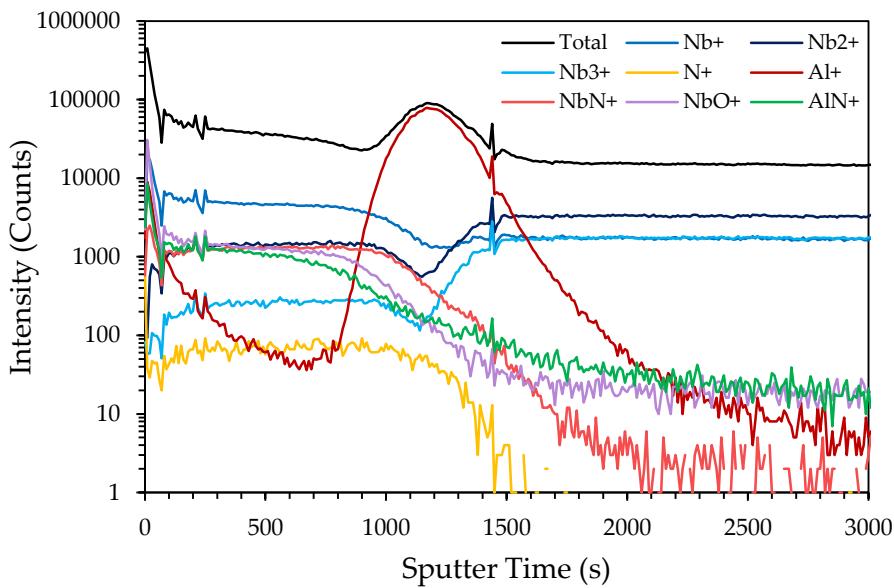
Intergranular oxygen



SIMS Courtesy of Ulrike Koch (Laboratory for Analytical Chemistry, University of Siegen)

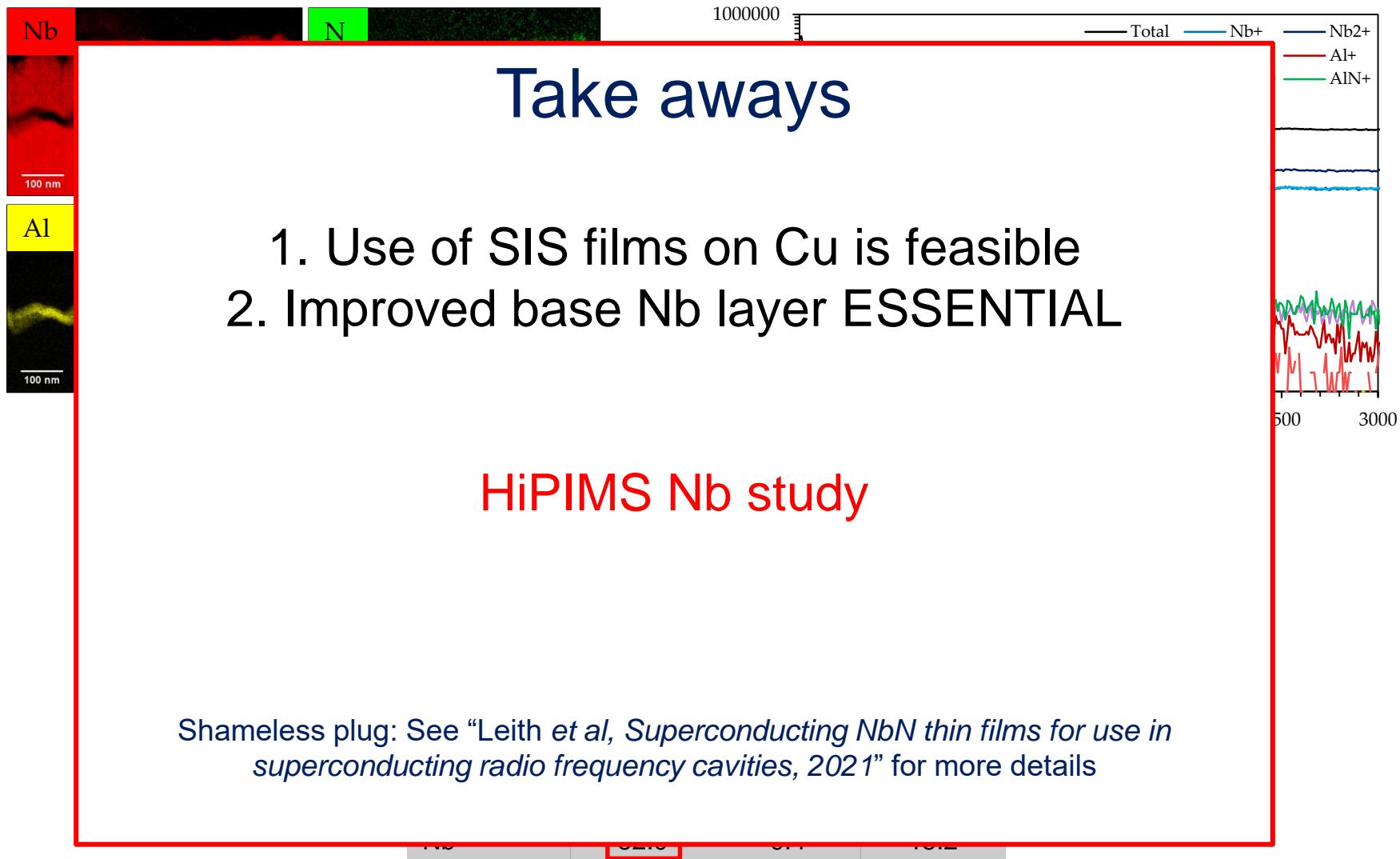


Intergranular oxygen



Sample (NbN)	H _{en} (mT)	Nb T _c (K)	NbN T _c (K)
SIS-1 (120)	64.5	9.4	14.7
SIS-2 (118)	14.5	9.2	14.5
SIS-3 (78)	24.0	9.2	14.0
SIS-4 (147)	26.5	9.4	14.9
Nb	52.0	9.4	15.2

SIMS Courtesy of Ulrike Koch (Laboratory for Analytical Chemistry, University of Siegen)

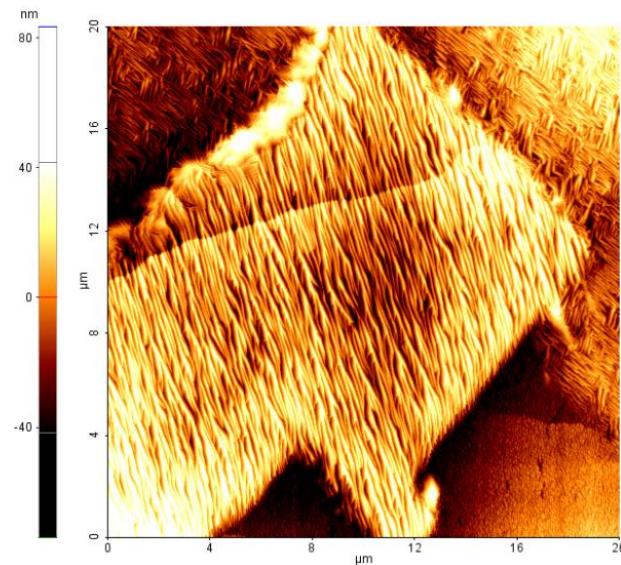


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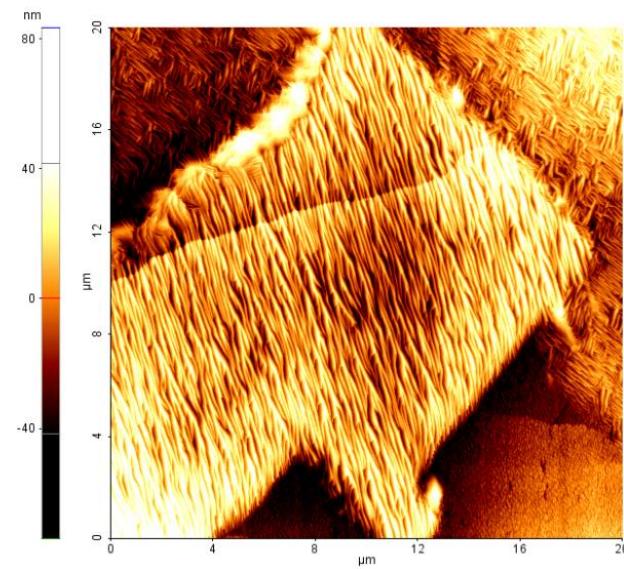
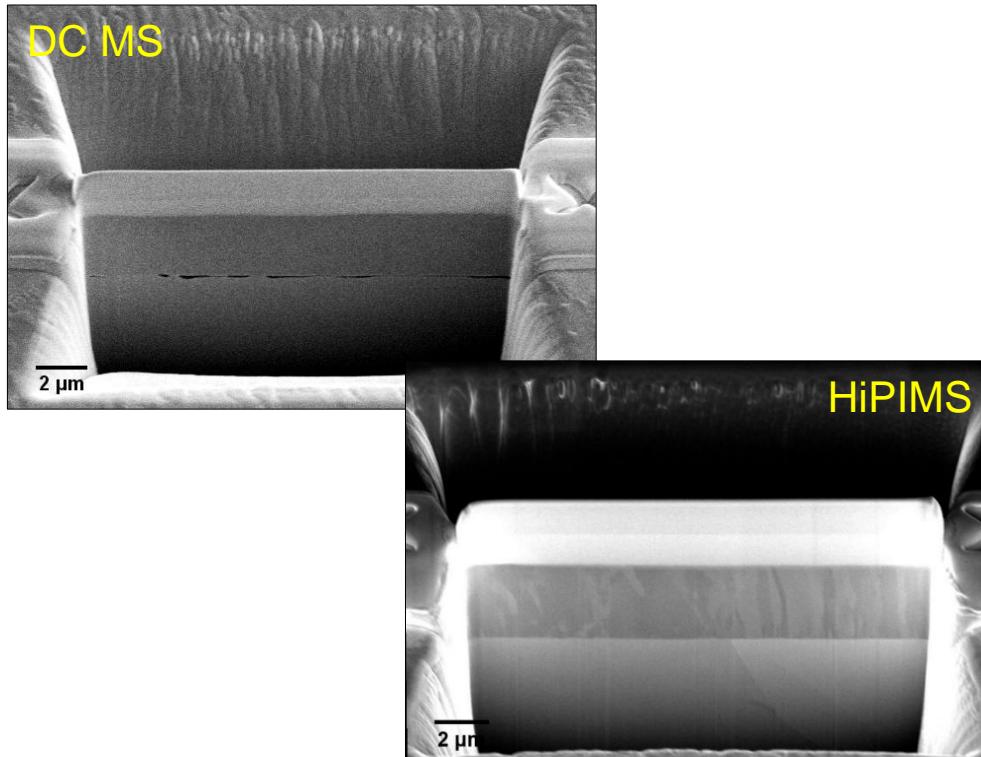
- Surface topography similar for all samples.
 - Damage at high substrate bias (> 150 V)



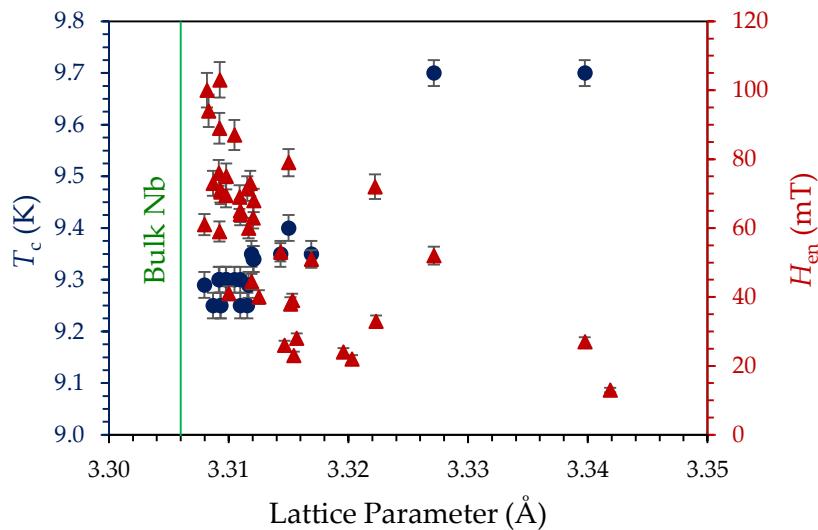
- Surface topography similar for all samples.
 - Damage at high substrate bias (> 150 V)
- Reduced average surface roughness:
 - Large GB influence



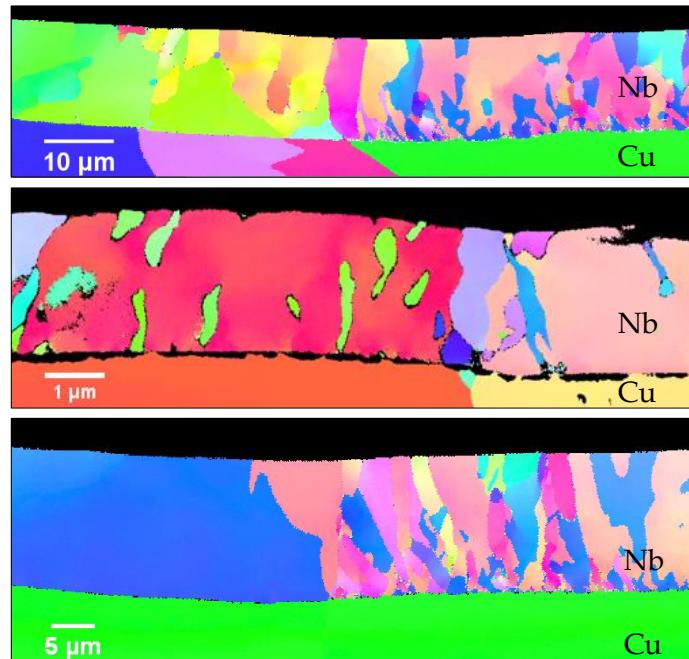
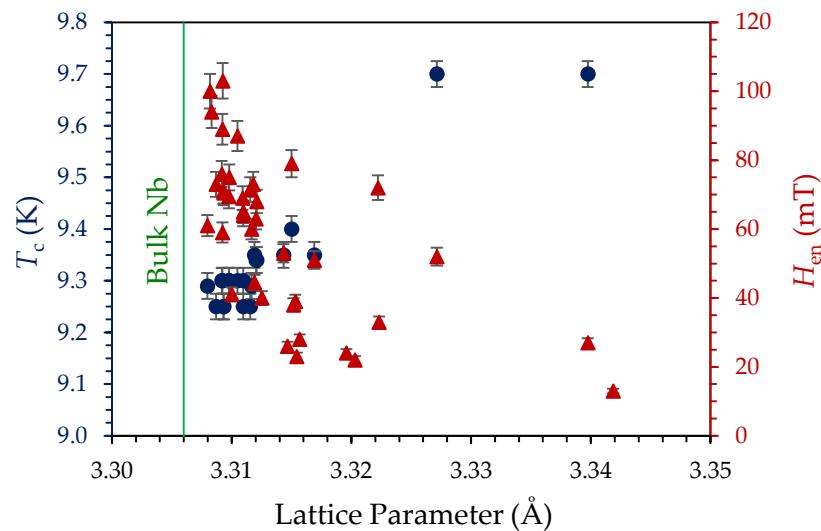
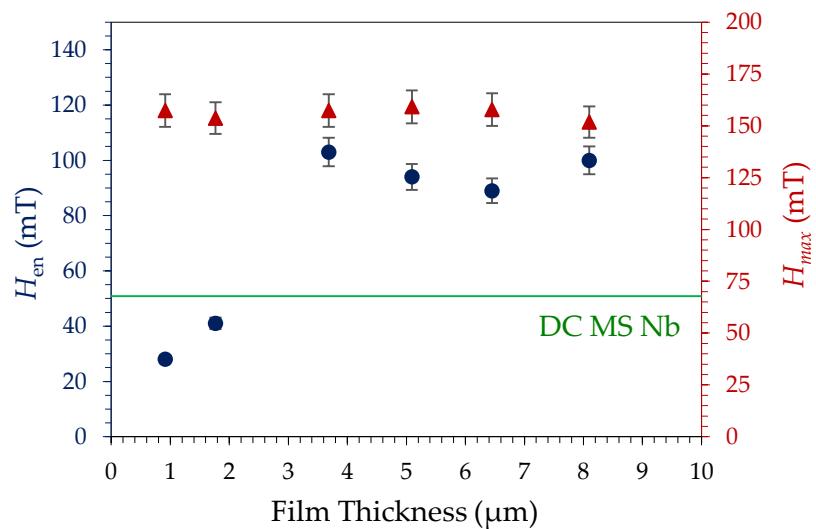
- Surface topography similar for all samples.
 - Damage at high substrate bias (> 150 V)
- Reduced average surface roughness:
 - Large GB influence
- Interface significantly improved.
 - 85% reduction in interfacial voids



- Bulk-like films perform better
 - Lower stress, bulk-like T_c , improved H_{en}
- Duty Cycle displays a relatively small influence
 - Specific maximums still observed

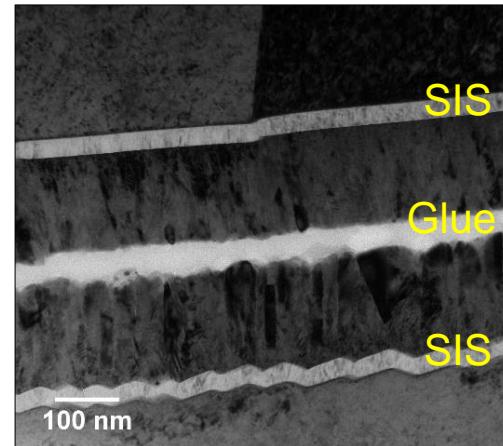


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- Duty Cycle displays a relatively small influence
 - Specific maximums still observed
- **Film Thickness** influences
 - “Transition zone”

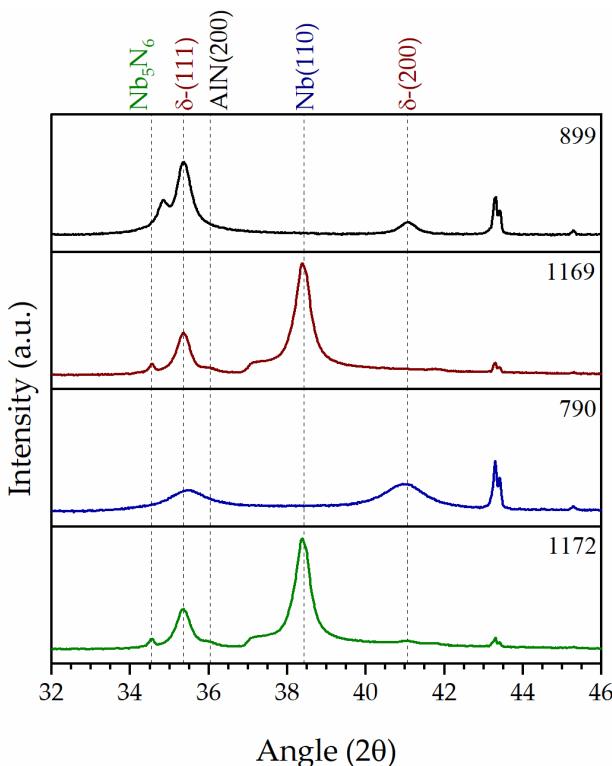
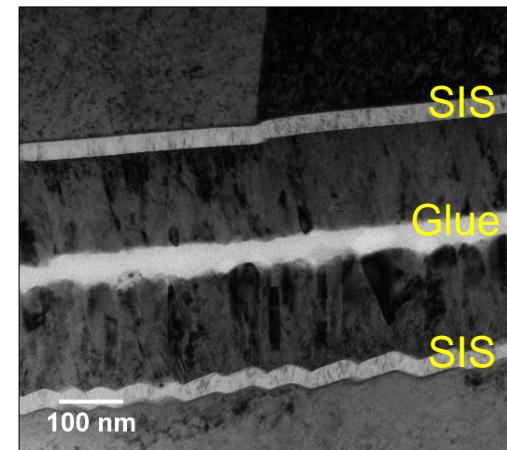
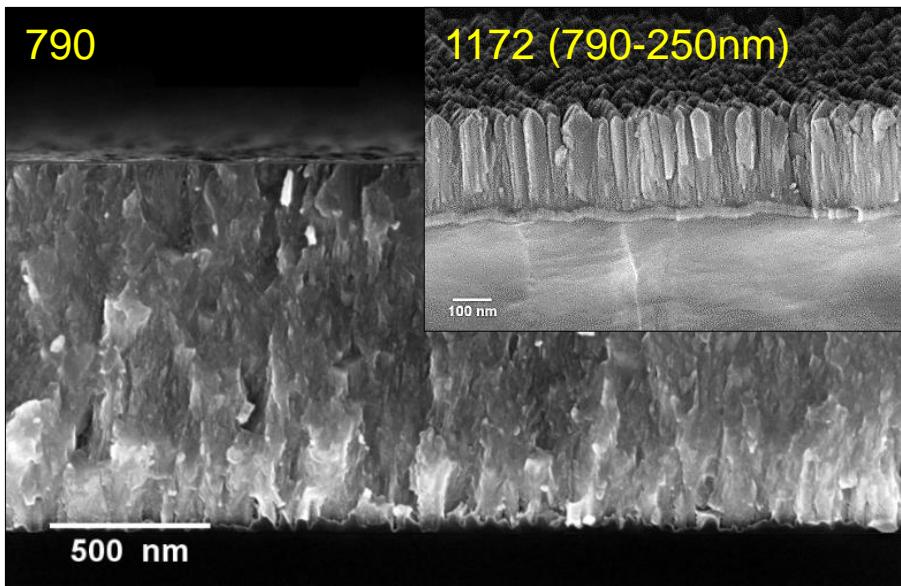


Thank you to G. Rosaz for XRF measurements

- Two SIS film series
 - 4 x Sample 899 recipe (High T_c)
 - 3 x Sample 790 recipe (High H_{en})
- HiPIMS Nb influence on AlN and NbN



- Two SIS film series
 - 4 x Sample 899 recipe (High T_c)
 - 3 x Sample 790 recipe (High H_{en})
- HiPIMS Nb influence on AlN and NbN
- Microstructure and orientation change due to table rotation!



NbN Superconducting performance reliance

- (899) vs. (790)

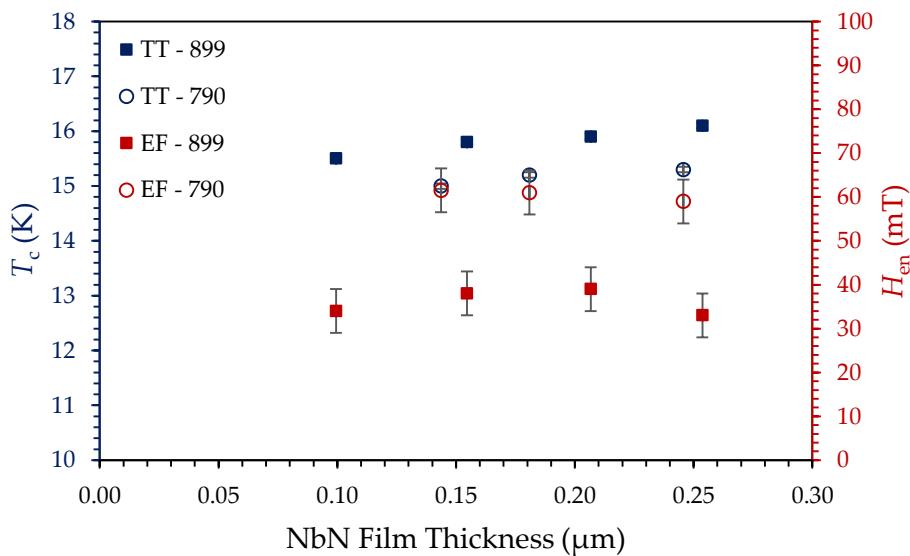
Sample	H_{en} (mT)	Nb T_c (K)	NbN T_c (K)
1165 (207nm)	39.0	9.3	15.9
1166 (155nm)	38.0	9.3	15.8
1167 (99nm)	34.0	9.3	15.5
1169 (254nm)	33.0	9.3	16.1
1170 (181nm)	61.0	9.3	15.2
1171 (144nm)	61.5	9.4	15
1172 (246nm)	59.0	9.3	15.3
HiPIMS Nb	103.0	9.35	-

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HiPIMS Nb	103.0	9.35	-

H_{en} NbN film thickness dependence



NbN Sup.



Sample

1165 (2)

1166 (1)

1167 (9)

1169 (2)

1170 (1)

1171 (1)

1172 (2)

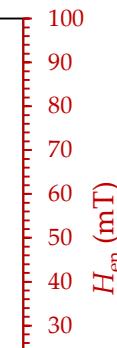
HiPIMS

Take aways

1. Definite divide in SIS film performance based on NbN recipe – Pursue higher entry field!

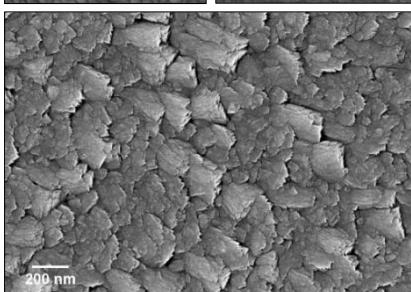
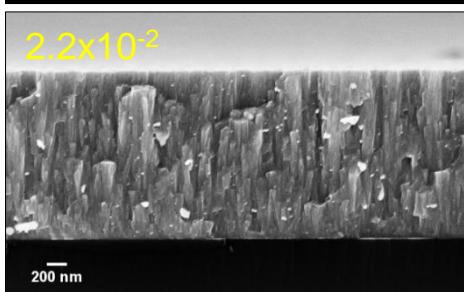
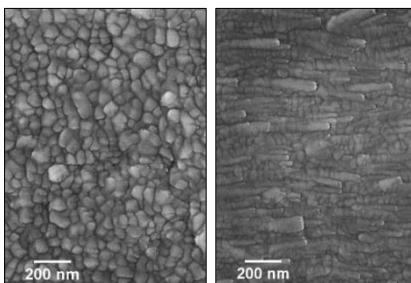
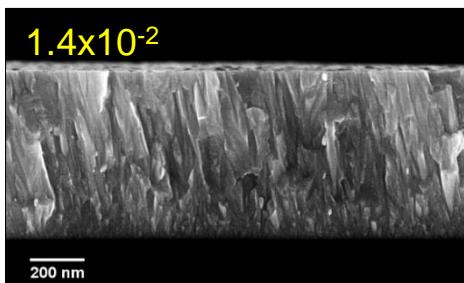
HiPIMS NbN Study

2. Complete rotation of table problematic.
Implement a “pulse” in front of the target.

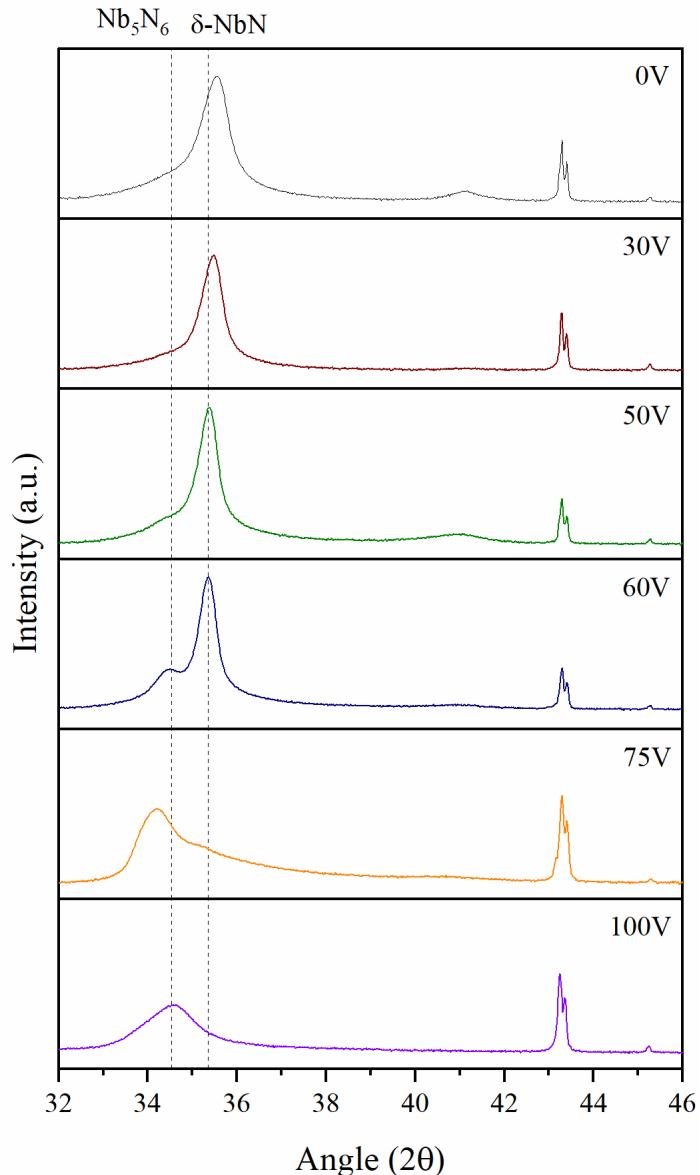
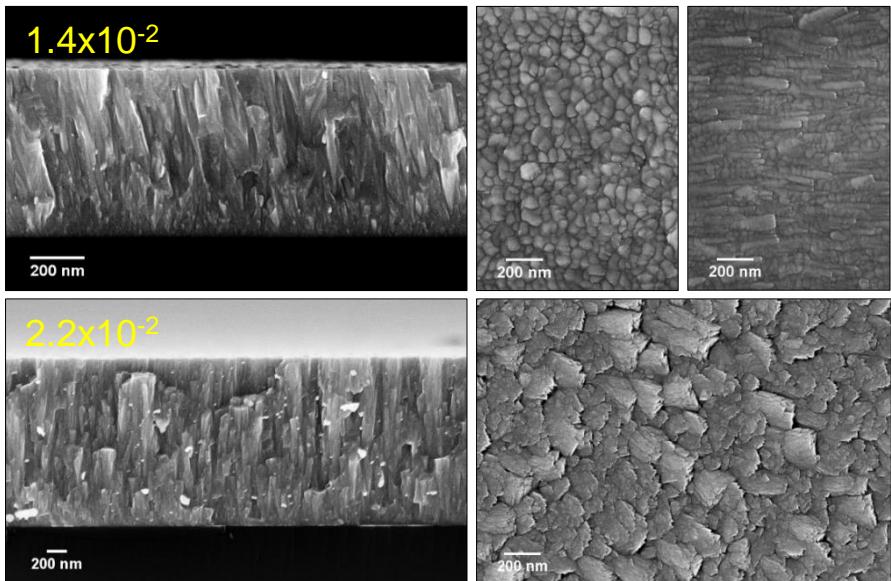


0.30

- Similar HiPIMS parameters to Nb
- Similar trends to DC MS NbN
- Improved surface roughness and density



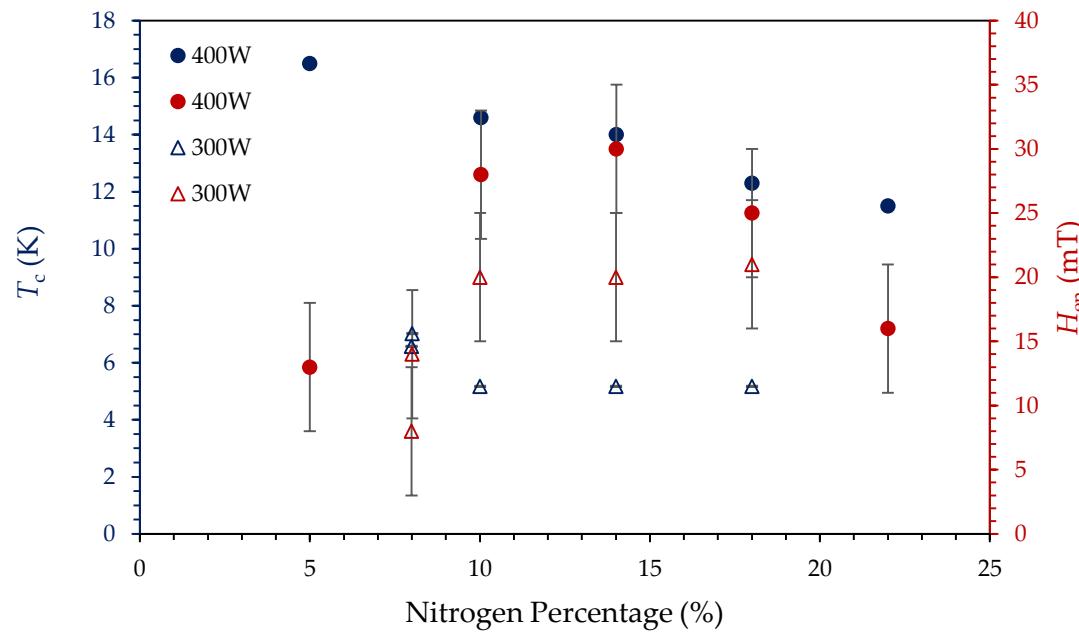
- Similar HiPIMS parameters to Nb
- Similar trends to DC MS NbN
- Improved surface roughness and density
- High Bias effects
 - Change of phase (> 60 V)
 - Loss of superconductivity (> 75 V)



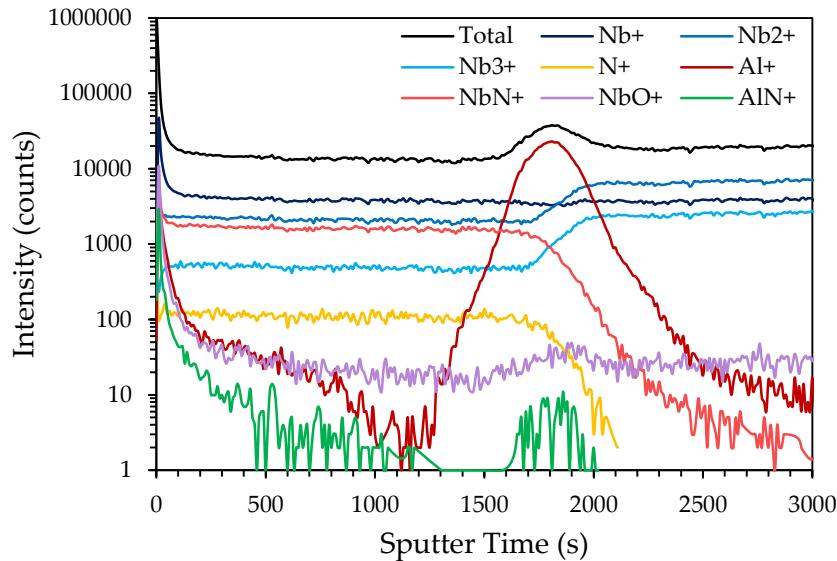
Significant superconductivity improvements over DC MS

- Highest $T_c = 16.5$ K
- Highest $H_{en} = 30$ mT (DC MS = 13 mT)
- Ave $H_{en} >$ DC MS Maximum

Interplay between p_{cath} , P_{dep} and $N_2\%$

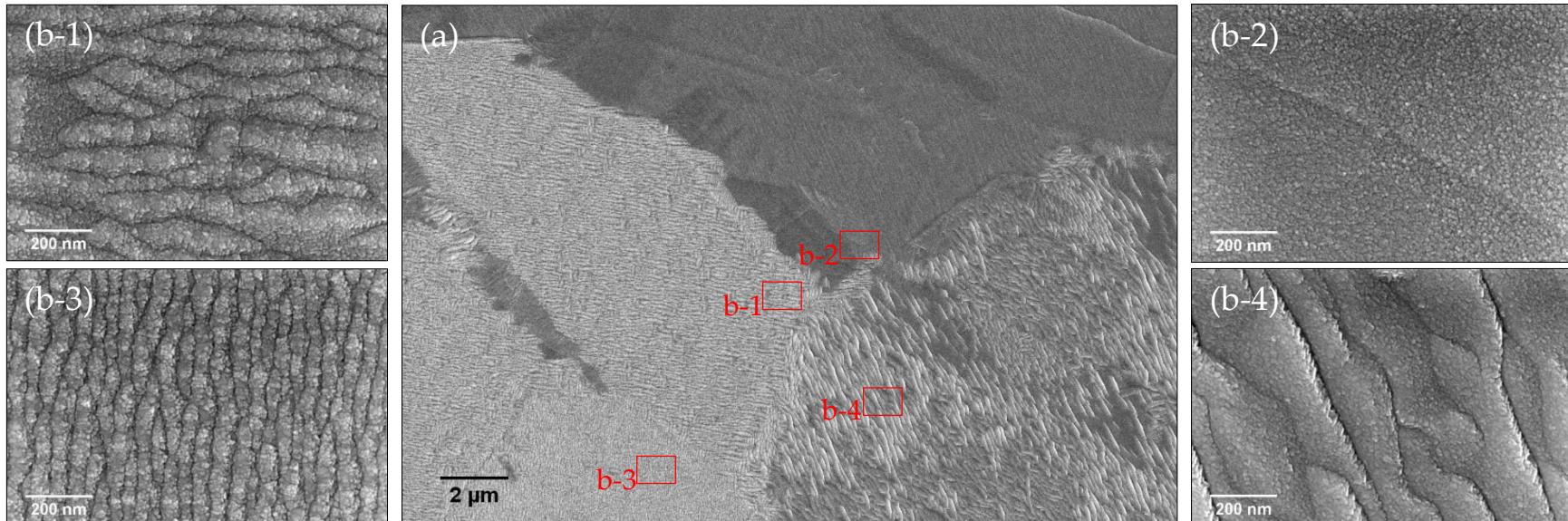
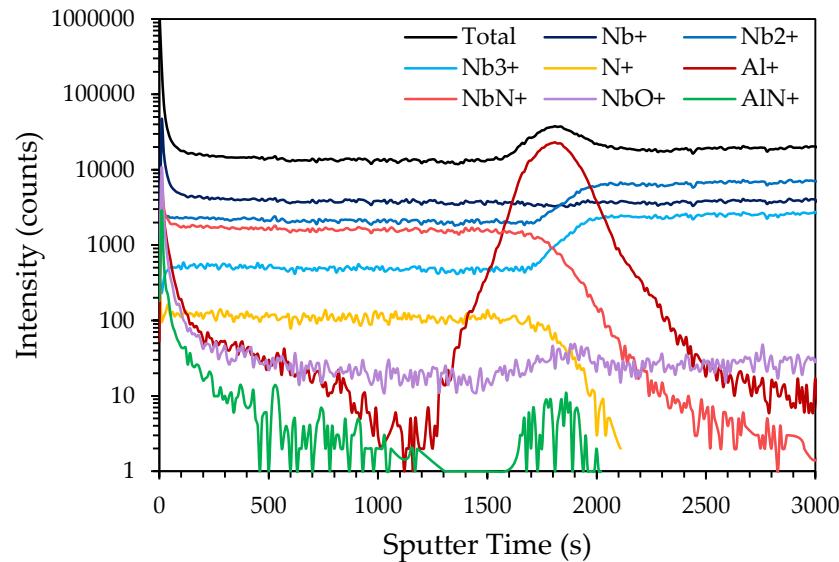


- Multiple HiPIMS SIS series
 - AlN 8 + 30 nm and NbN (100 to 200 nm)
 - Pulsing instituted for AlN + NbN
- Oxygen content reduction



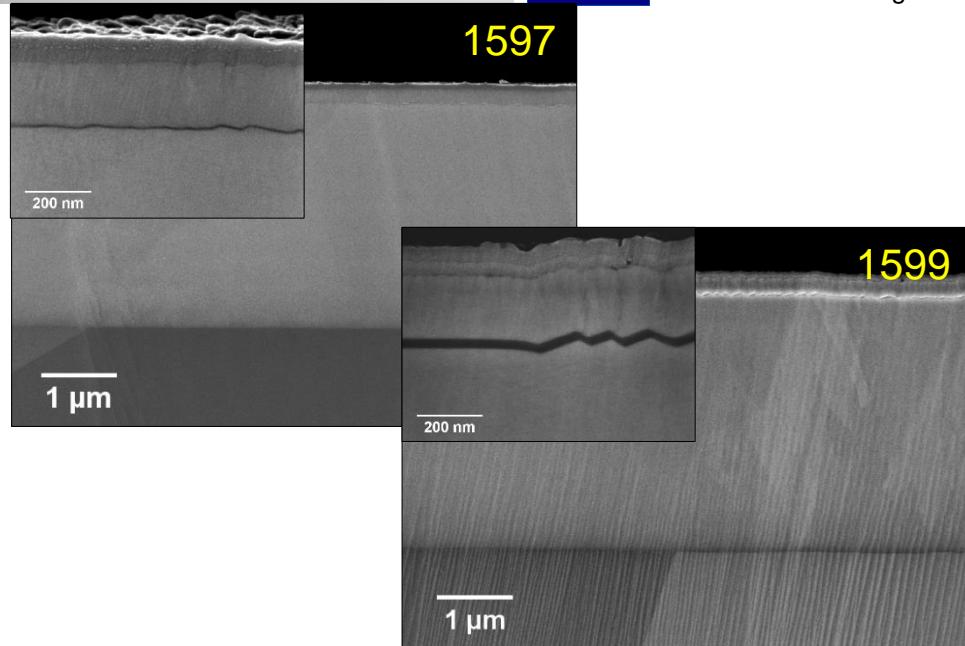
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- Multiple HiPIMS SIS series
 - AlN 8 + 30 nm and NbN (100 to 200 nm)
 - Pulsing instituted for AlN + NbN
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- SIS film morphology dominated by HiPIMS Nb
 - NbN “superimposed” on top of Nb + AlN

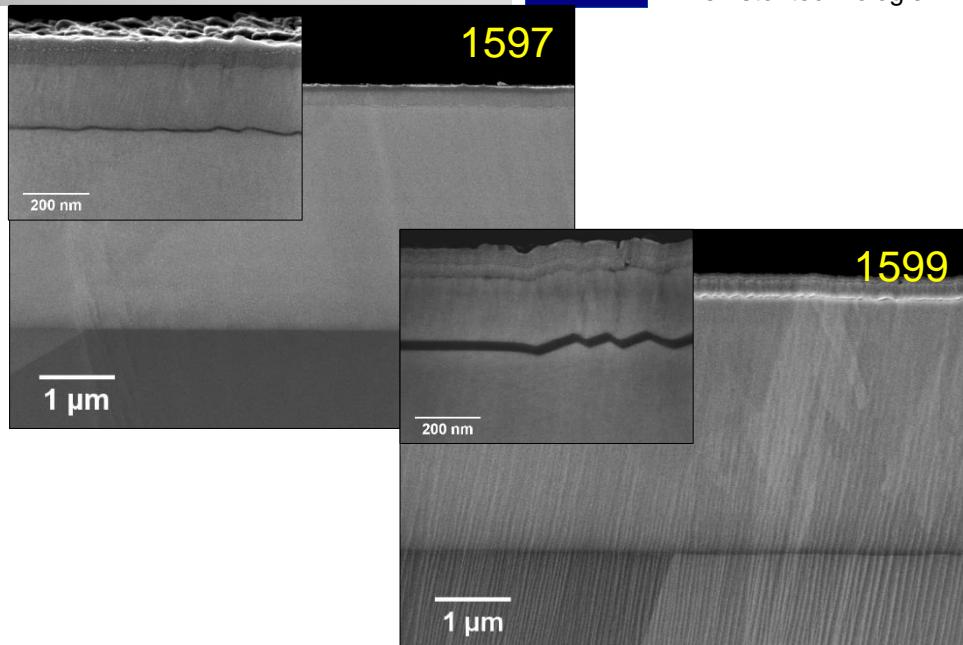
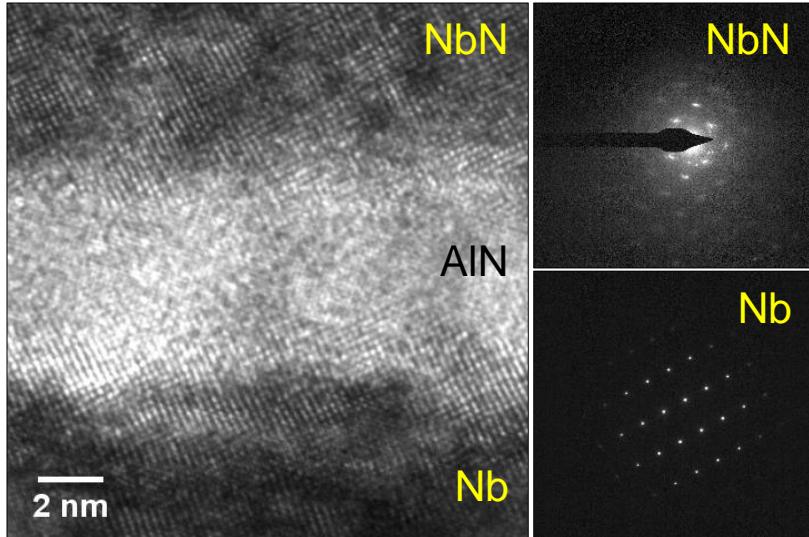


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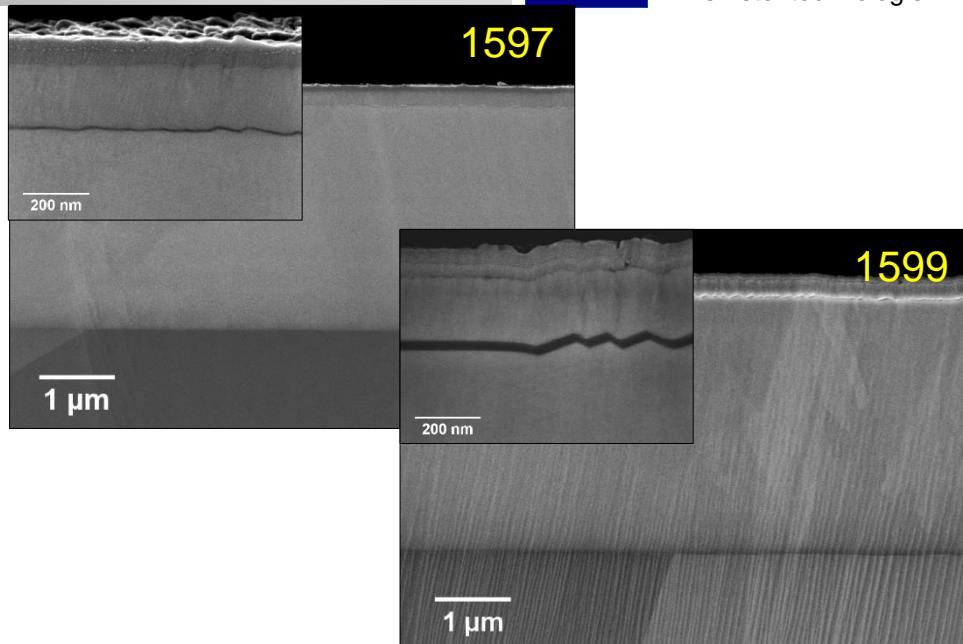
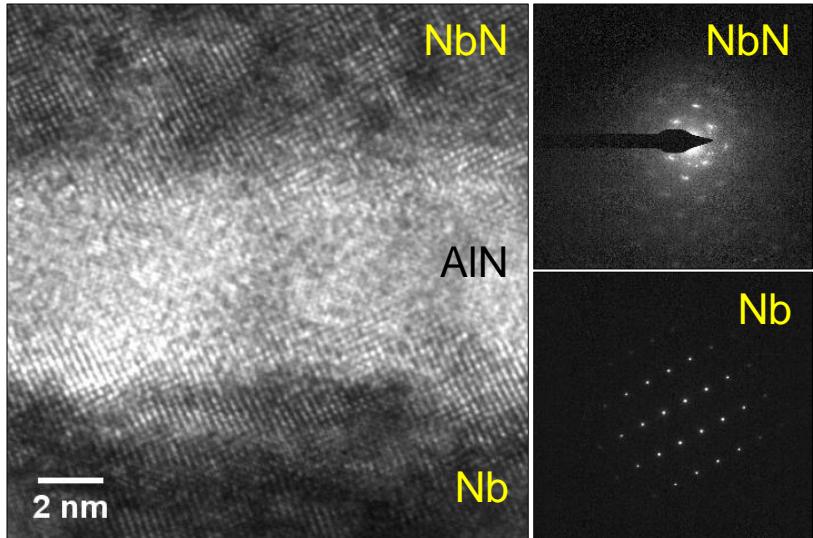
- Improved surface roughness and density



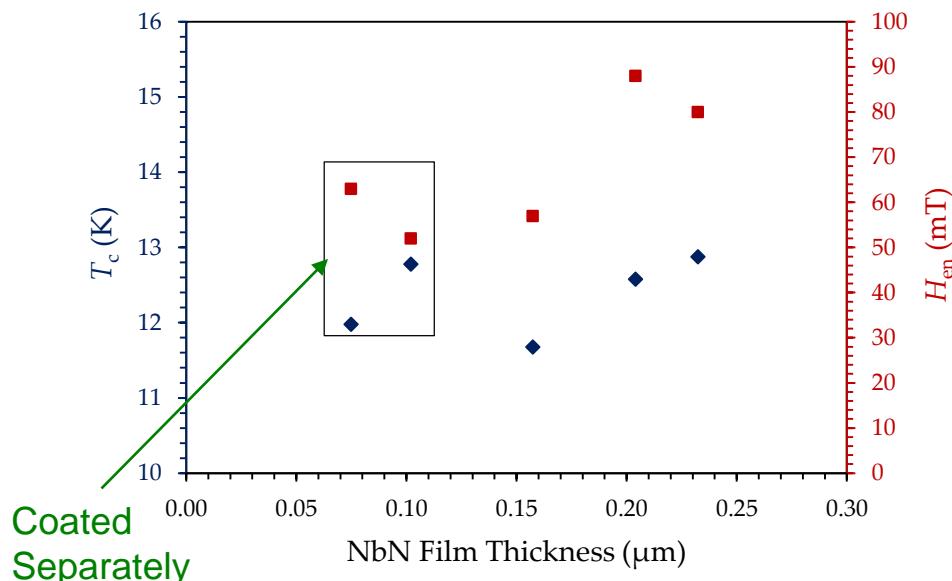
- Improved surface roughness and density
- Coherent epitaxial growth of SIS layers



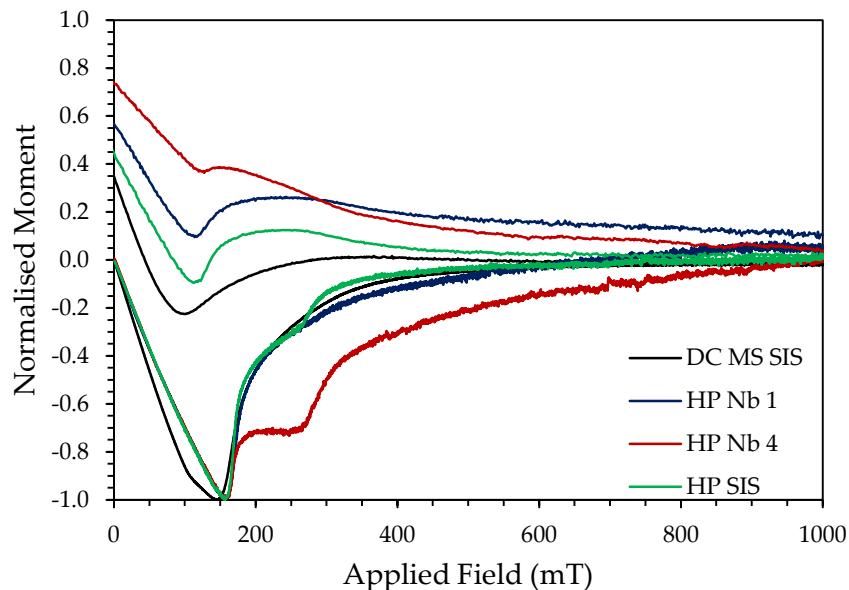
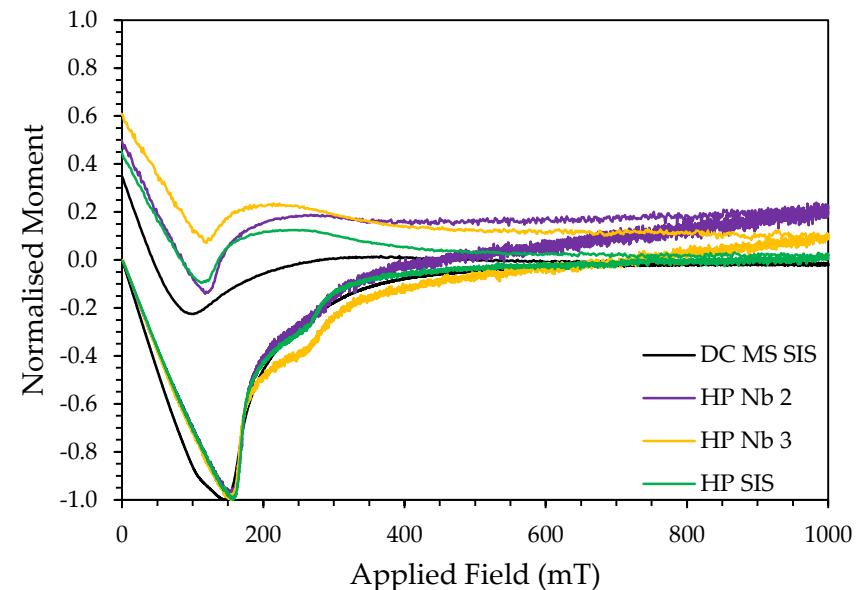
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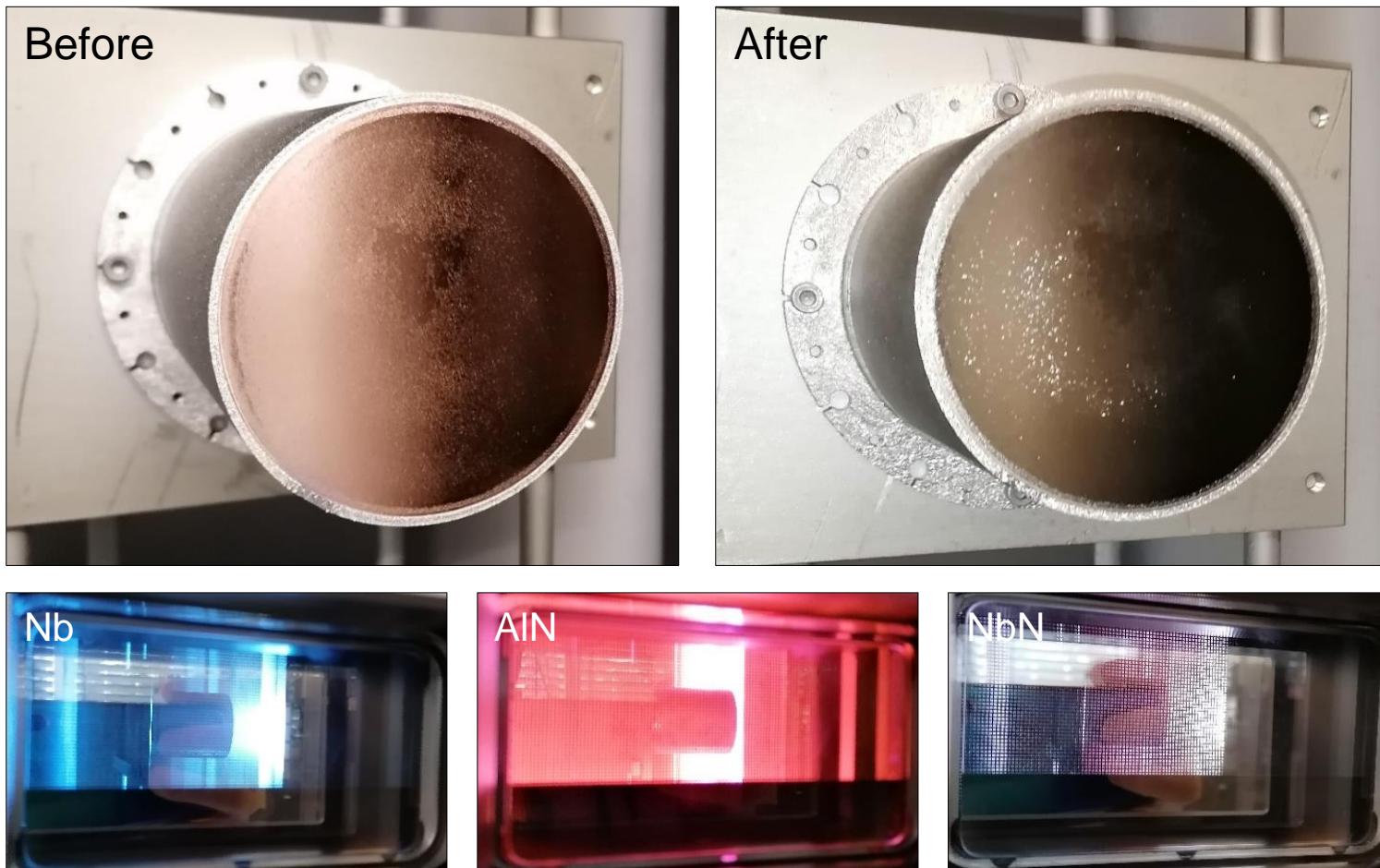
- Decreased T_c in SIS vs original
- H_{en} thickness dependence on recipe
 - Cleaner films (HiPIMS) = Thicker layer
- Increased H_{en} for HiPIMS SIS films
 - (88 mT vs. 64.5 mT)



- Significant improvements offered by HiPIMS – Optimisation possible
- Best DC MS SIS film displays smallest magnetisation loop
- HiPIMS NbN shows more pronounced “dip” but earlier separation.
- Highest H_{en} samples vs. Lowest H_{tr} Measurement in oscillating field required
- Final HiPIMS SIS samples still to be tested

Best performing H_{en} Best performing H_{tr}

*Measured in parallel field at 4.22 K



QPR test results detailed by D. Tikhonov – 18/03

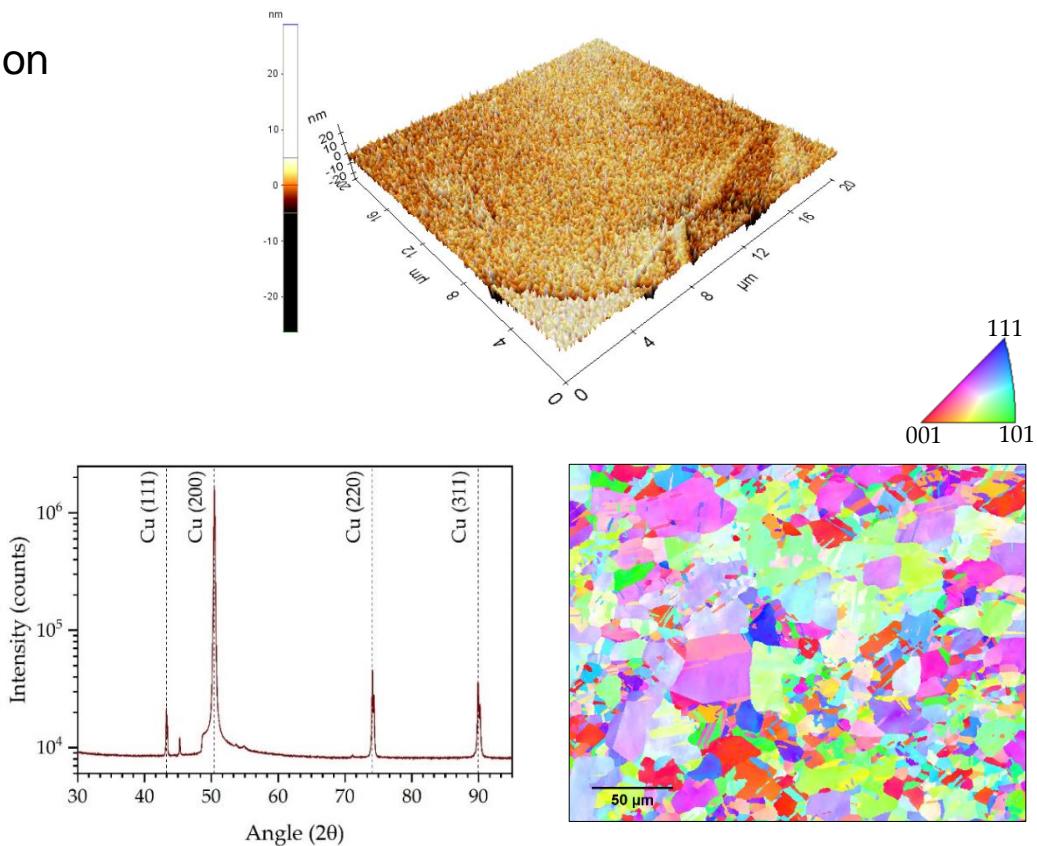
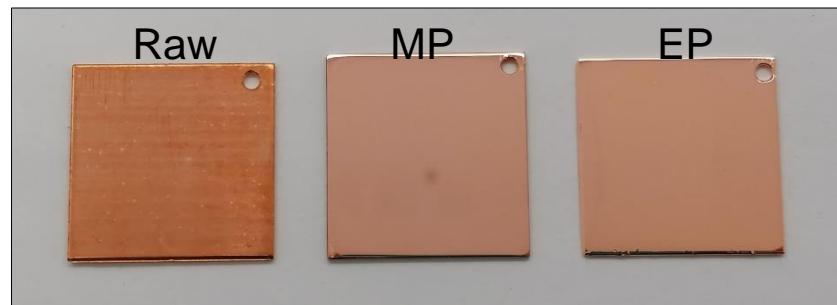
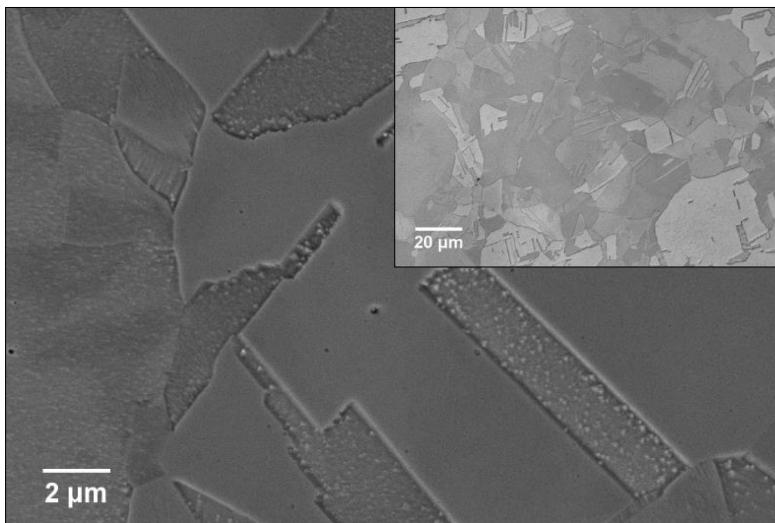
Thanks for your Attention!



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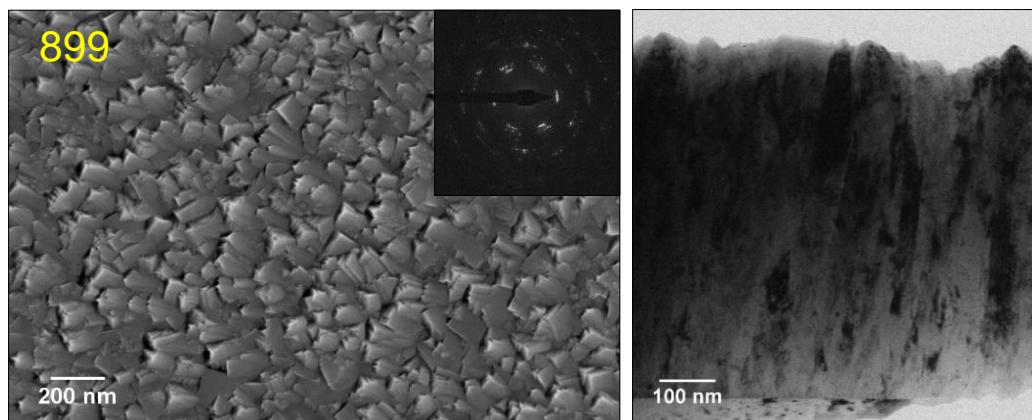
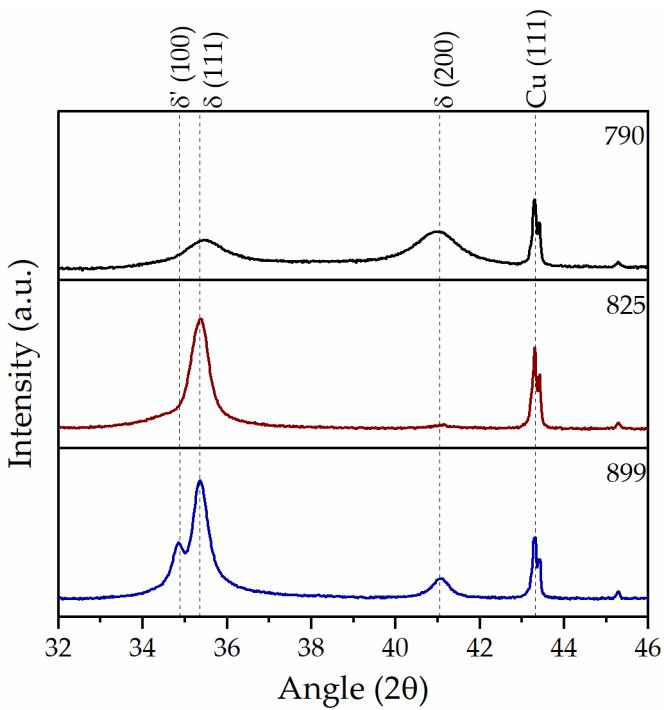
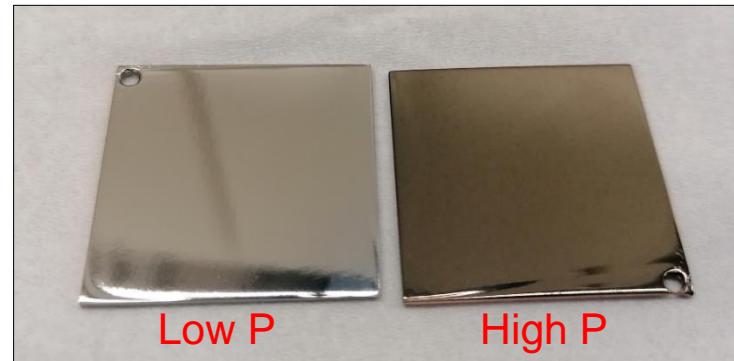
Extra Slides

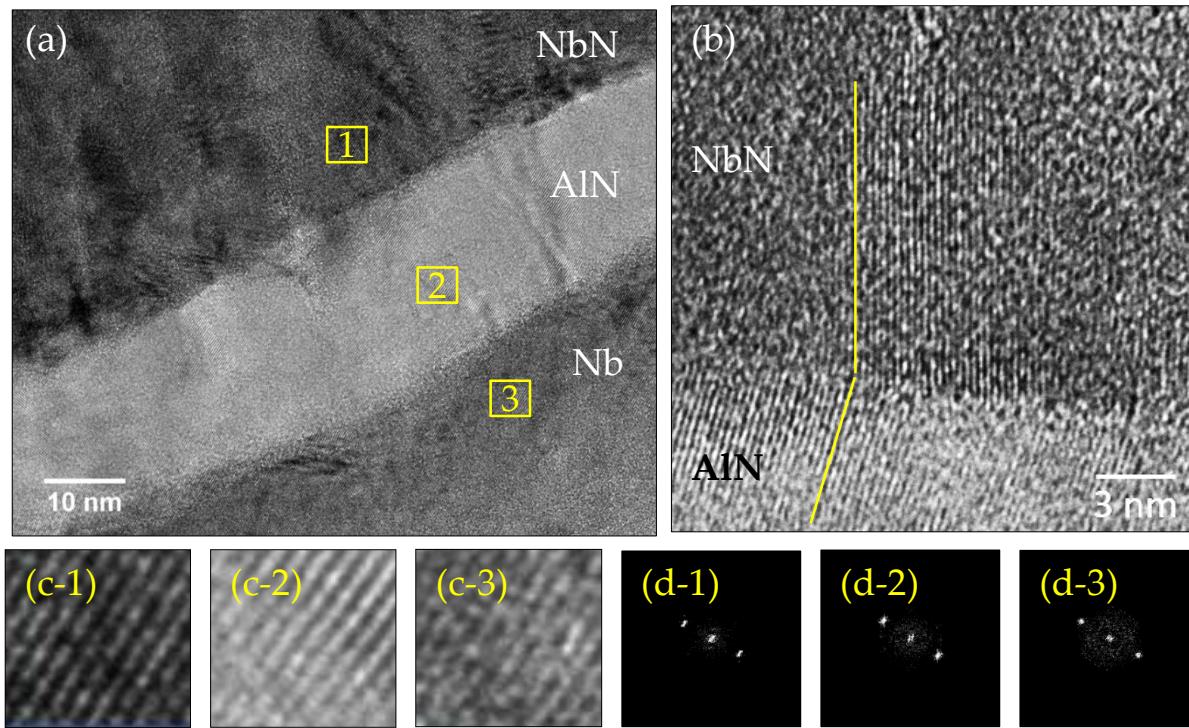
- OFHC Cu substrates (25 x 25 mm)
- MP + EP (1 hour)
 - Large step edge GB (**Max 20 nm**)
- $S_q = 2.58 \pm 0.26 \text{ nm}$
- Polycrystalline, (200) preferred orientation

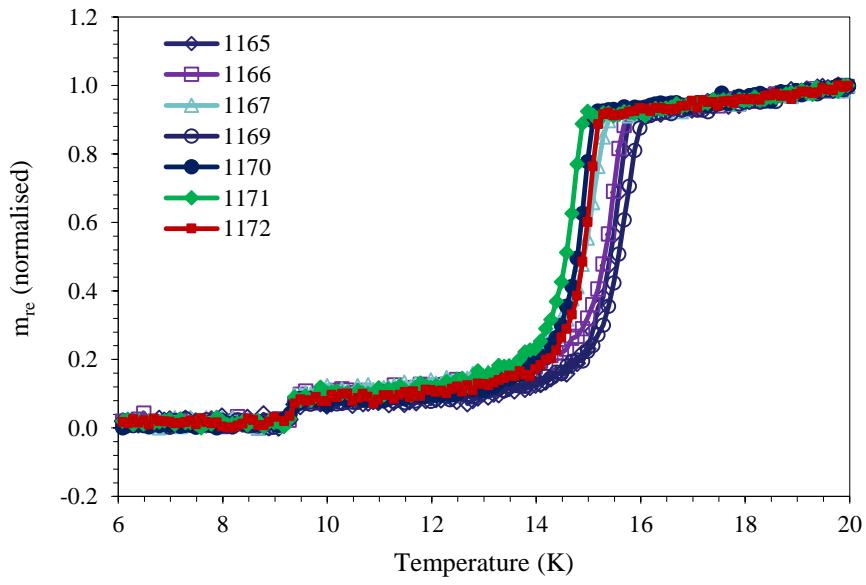


Optimised Coating:

- 8% N₂
- Intermediate Pressure (1.4E-2 mbar)
- Substrate Bias (75 V)
- Increased Cathode Power
- $T_c = 16.1 \text{ K}$, $H_{en} = 5 \text{ mT}$
- $S_q = 6.36 \pm 0.42 \text{ nm}$
- δ-NbN(111) with small δ'-NbN

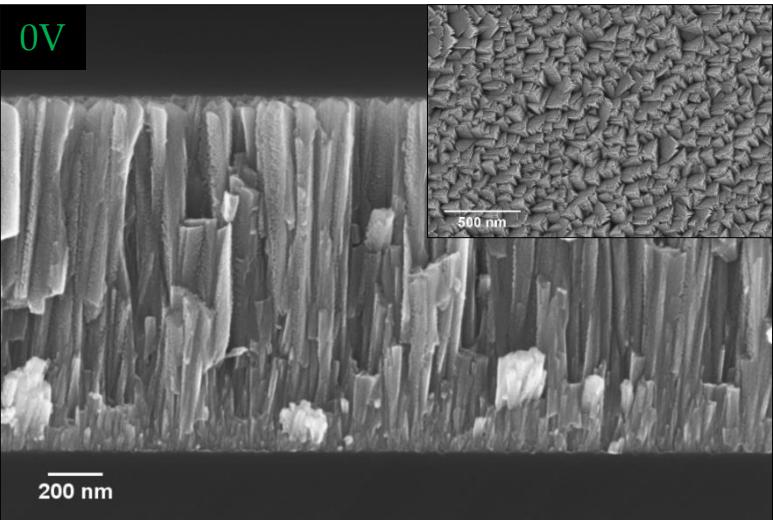




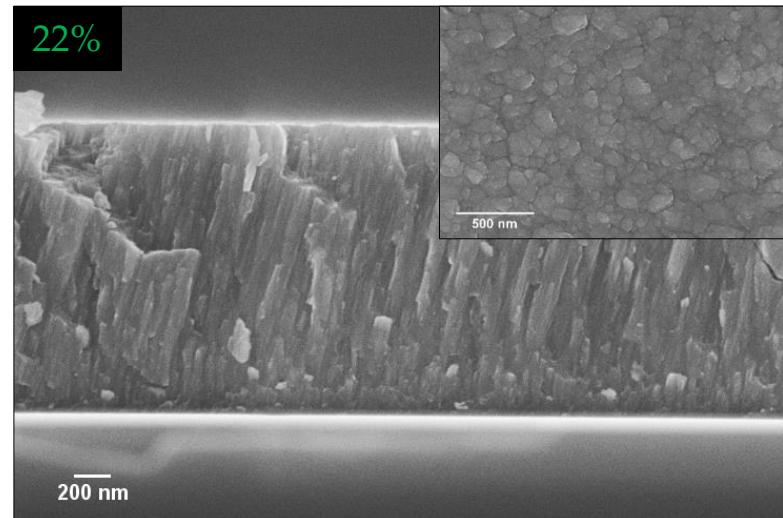
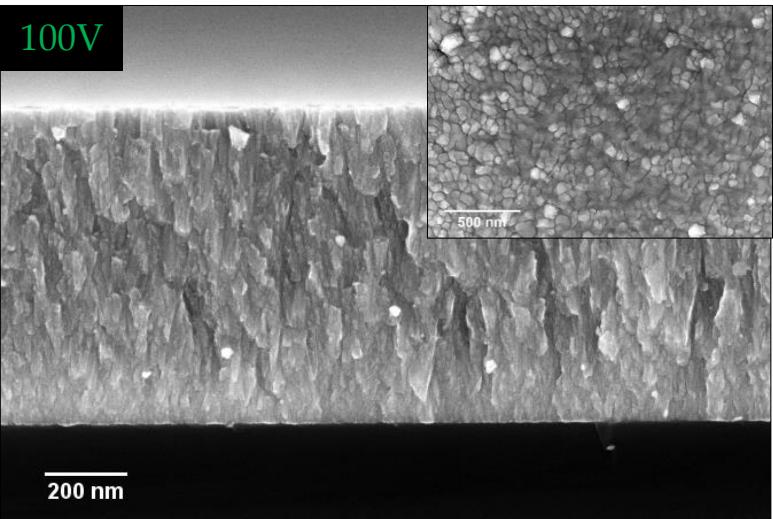
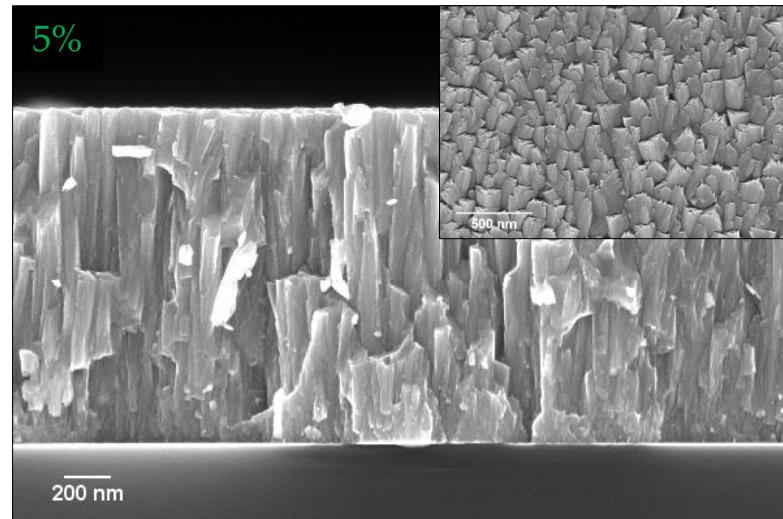


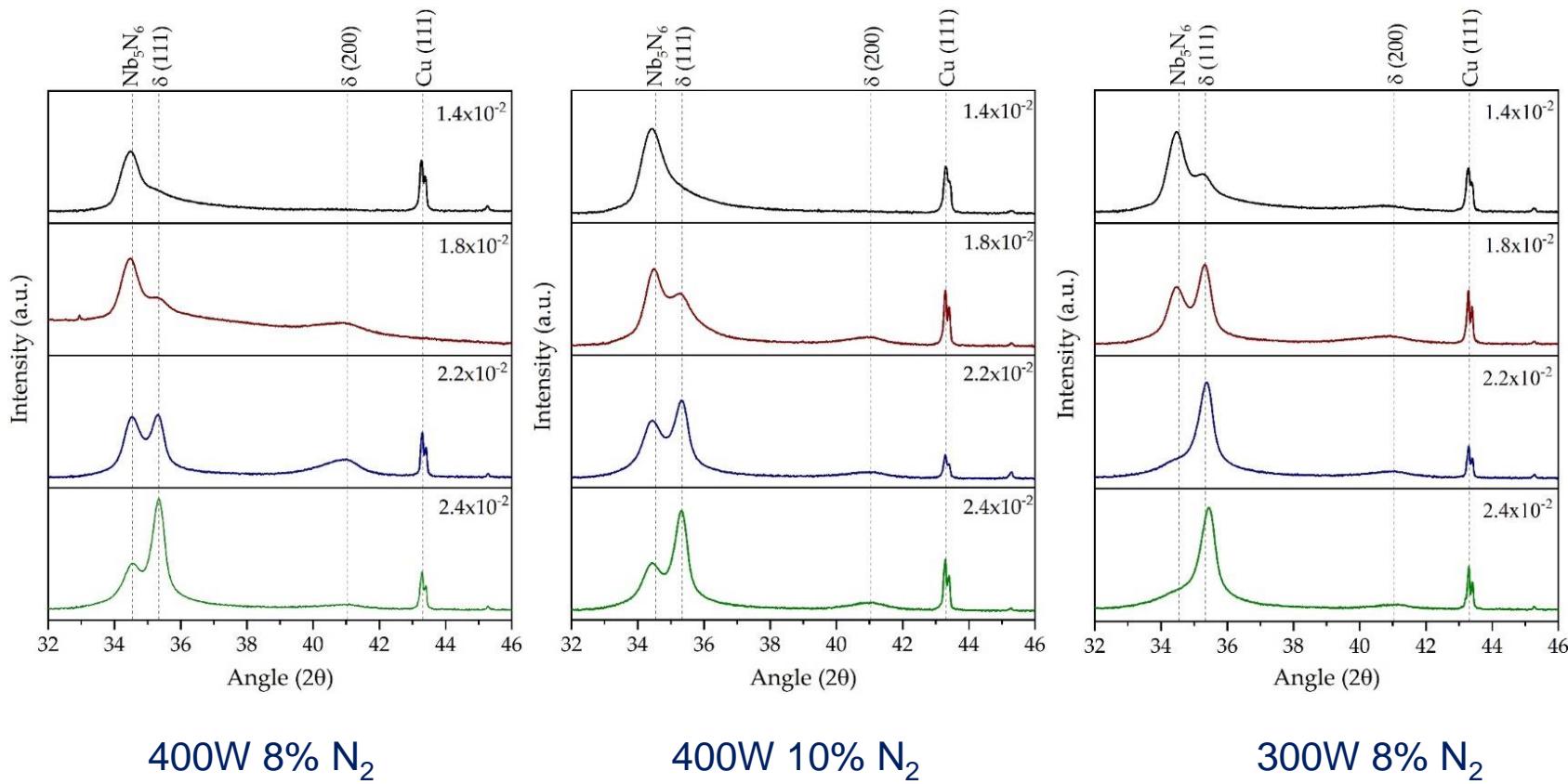
Parameter	Value
Cathode Power	300 to 600 W
Deposition Pressure	8×10^{-3} - 1.8×10^{-2} mbar
HiPIMS Pulse Length	80 to 200 μ s
HiPIMS Pulse Frequency	800 to 2000 Hz
Duty Cycle (Calculated)	2 to 20 %
Substrate Bias	0 to - 250 V
Substrate Temperature	115 to 290 °C
Film Thickness.	0.91 to 8.10 μ m

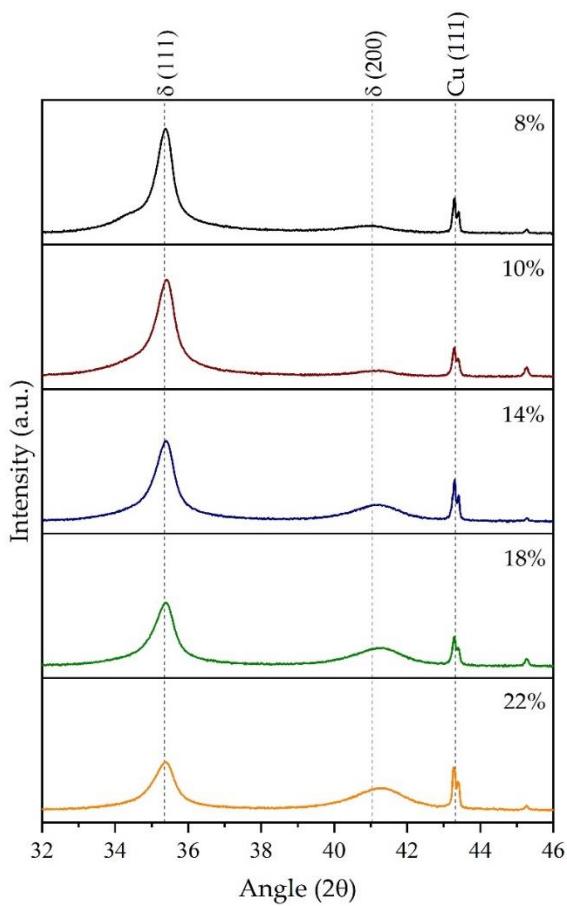
Substrate Bias



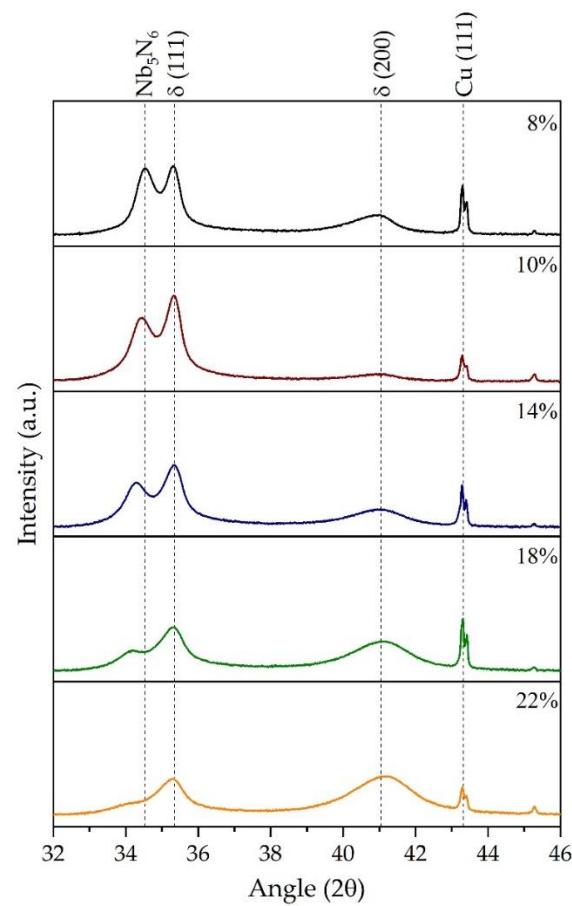
Nitrogen Percentage





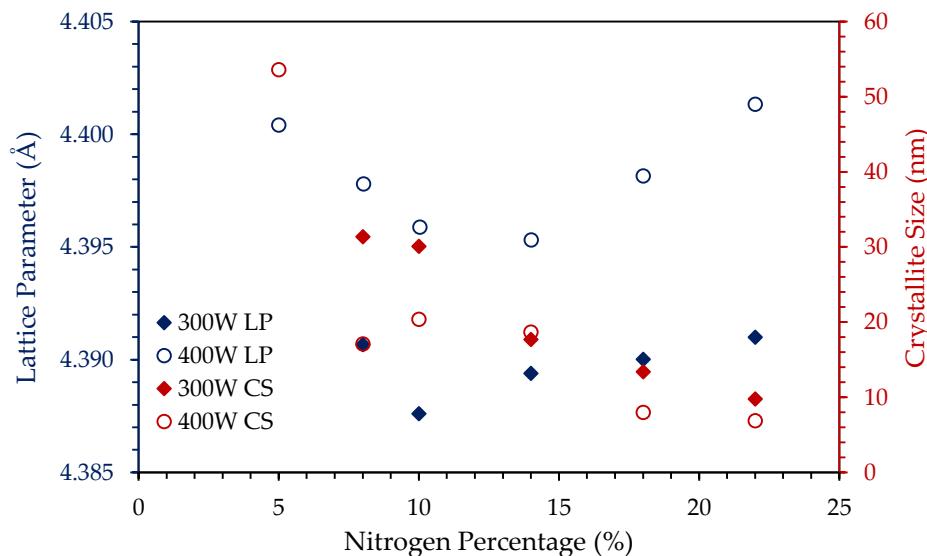
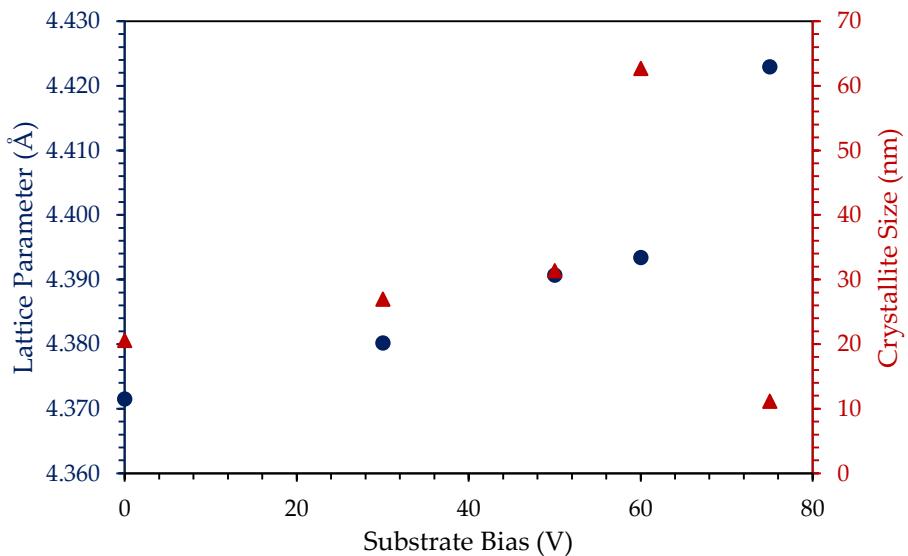


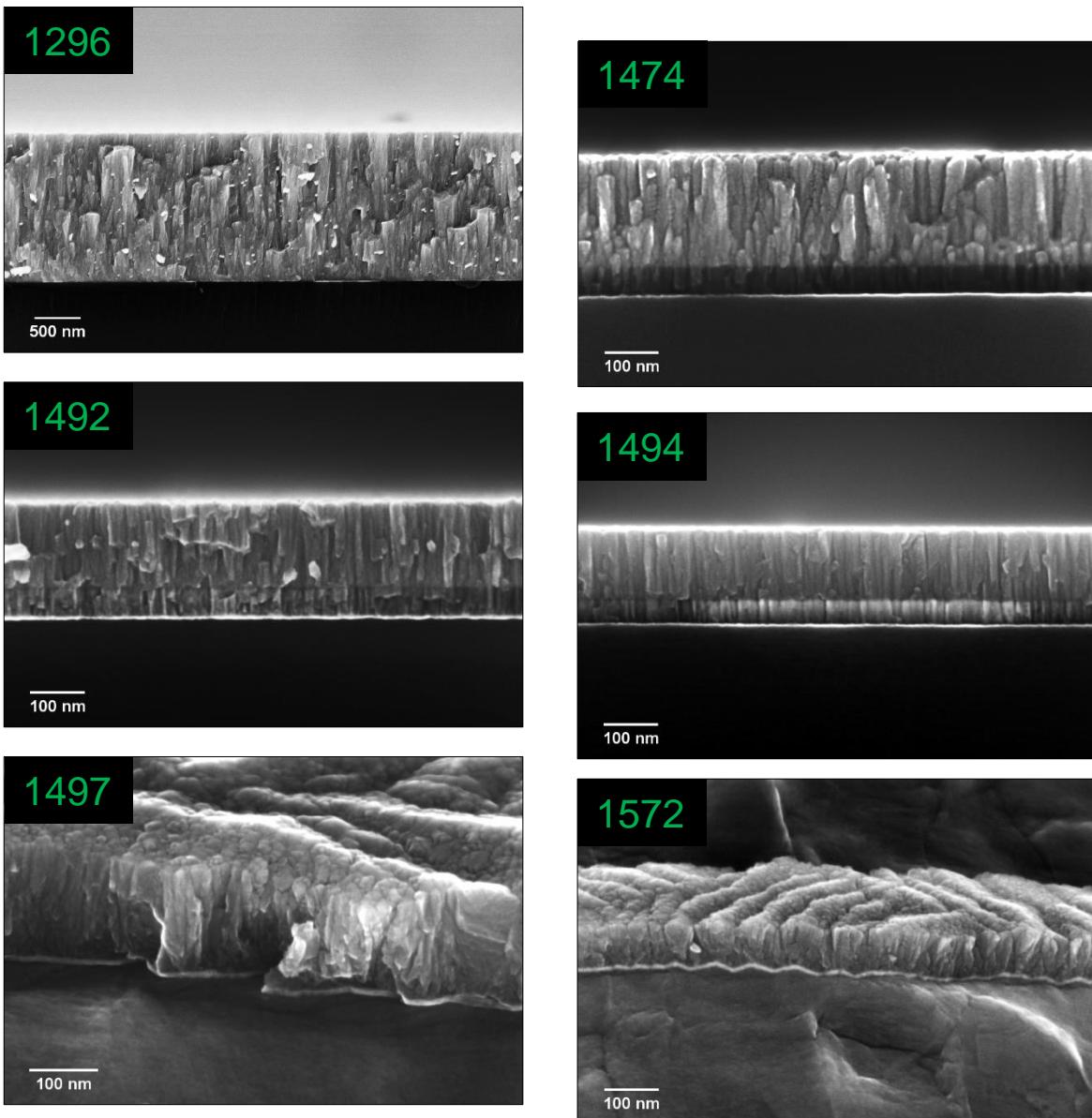
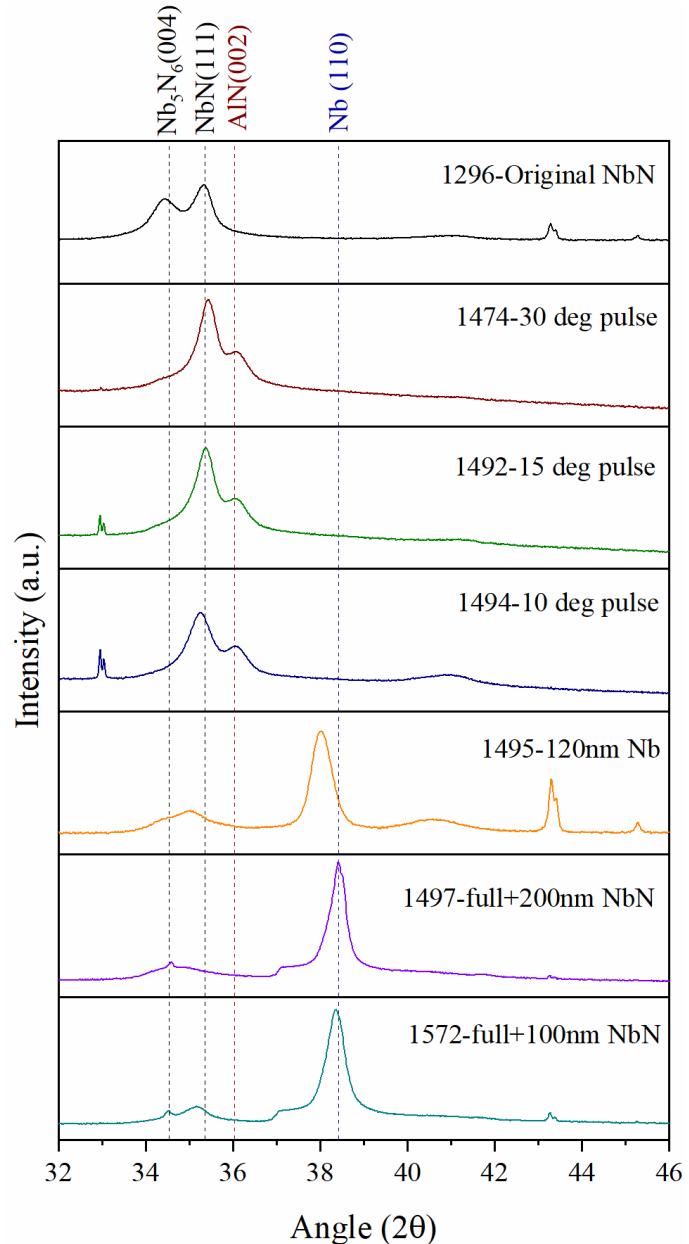
300W

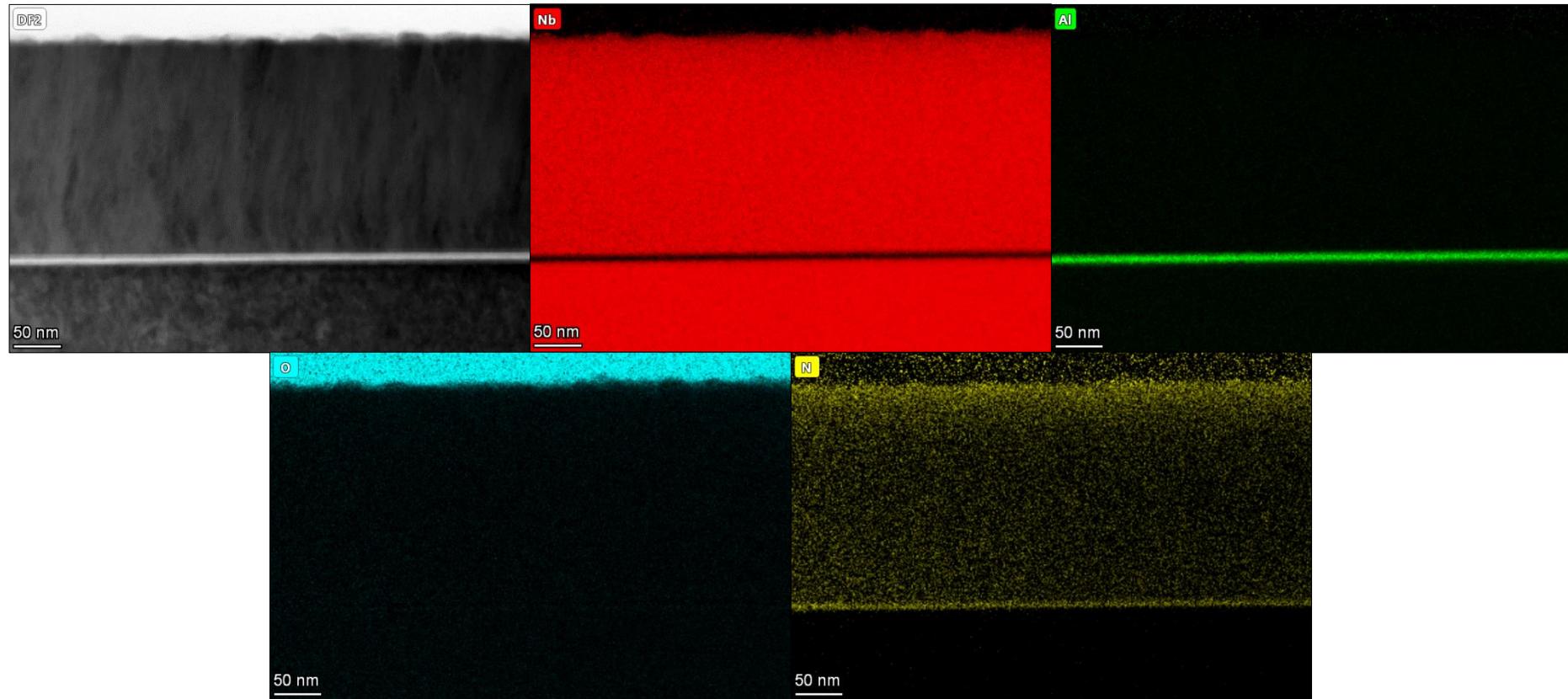


400W

- Lattice Parameter dependent on specific deposition parameters. Increases with:
 - Increasing substrate bias
 - Decreasing Pressure
 - Increasing Cathode Power
- Reaches a specific minimum for N₂% - related to phase formation
- Crystallite size increases with:
 - Decreasing cathode power
 - Decreasing N₂%
 - Increasing substrate bias. Except at high values due to phase change.
 - Increasing deposition pressure







Recipe

- HiPIMS Nb (~3.8 µm)
 - Sample 1077 recipe
 - 400 W (1000 Hz, 120 µs)
 - 8e⁻³ mbar
- AlN (8 or 24 nm)
 - 3500 W, 6e⁻³ mbar, 100% N₂
 - 3x10⁰ pulse
- HiPIMS NbN (180 nm)
 - Sample 1296 recipe (Highest H_{en})
 - 400 W (1000 Hz, 120 µs)
 - 2.2e⁻² mbar, 10% N₂
 - 56x10⁰ pulses